Docket No.: 50006-128 **PATENT**

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of	:	Customer Number: 20277
Makoto NAGATA, et al.	:	Confirmation Number: 4496
Serial No.: 09/977,994	:	Group Art Unit: 2857
Filed: October 17, 2001	:	Examiner: Jeffrey R. West

For: METHOD AND APPARATUS FOR ANALYZING A SOURCE CURRENT WAVEFORM IN A SEMICONDUCTOR INTEGRATED CIRCUIT

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed more than three months after the U.S. filing date AND after the mailing date of the first Office Action on the merits, but before the mailing date of a Final Rejection or Notice of Allowance.

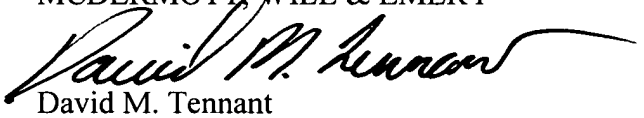
In accordance with 37 CFR 1.17(p), please charge the fee of $180.00 to Deposit Account No. 500417.

The article "Physical Design Guides for Substrate Noise Reduction in CMOS Digital Circuits" was referenced in a foreign search report and was previously filed in an IDS for the above-reference application. However, that reference was incorrectly cited and is resubmitted with the correct citation. Applicants became aware of "Quantitative Characterization of Substrate Noise for Physical Design Guides in Digital Circuits" just over three months ago. The Table of Contents for the "Proceedings of the IEEE 2000 Custom Integrated Circuits Conference" was recently obtained.

Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account 500417 and please credit any excess fees to such deposit account.

Respectfully submitted,

MCDERMOTT, WILL & EMERY



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INFORMATION DISCLOSURE CITATION IN AN APPLICATION

(PTO-1449)

ATTY. DOCKET NO.	SERIAL NO.
50006-128	**09/977,994**
APPLICANT: **Makoto NAGATA, et al.**	
FILING DATE: **October 17, 2001**	GROUP: **2857**

U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code2 (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		US			
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FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Code3-Number 4-Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation Yes	Translation No

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	
		Nagata, M., et al., "Physical Design Guides for Substrate Noise Reduction in CMOS Digital Circuits," IEEE Journal of Solid-State Circuits, Vol. 36, No. 3, (Mar. 2001).	
		Nagata, M., et al, "Quantitative Characterization of Substrate Noise for Physical Design Guides in Digital Circuits," IEEE 2000 Custom Integrated Circuits Conference, Orlando, Florida, May 21-24, 2000.	
		Table of Contents for the Proceedings of the IEEE 2000 Custom Integrated Circuits Conference, Orlando, Florida, May 21-24, 2000.	

EXAMINER	DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.